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AMENDMENTS TO THE CLAIMS

Please amend the claims as indicated in the following listing of all claims:

1. (Previously Presented) An integrated circuit comprising:  
a temperature sensor providing a temperature measurement of the integrated circuit;  
a programmable storage location storing a first temperature limit value, the  
programmable storage location accessible via an instruction executed by the  
integrated circuit; and  
compare logic coupled to the temperature sensor and the storage location to provide an  
indication of a comparison between the temperature measurement and the first  
temperature limit value,  
wherein the integrated circuit asserts a first temperature control signal which is supplied  
on a first output terminal of the integrated circuit when the temperature  
measurement is above the first temperature limit value.
2. (Cancelled)
3. (Previously Presented) The integrated circuit as recited in claim 1 wherein the  
integrated circuit deasserts the first temperature control signal, which is supplied on the first  
output terminal of the integrated circuit, when the temperature measurement indicated by the  
temperature sensor falls below a programmable second temperature limit value.
4. (Previously Presented) The integrated circuit as recited in claim 1 wherein the  
integrated circuit deasserts the first temperature control signal, which is supplied on the first  
output terminal of the integrated circuit, in response to access to a control location in the  
integrated circuit.
5. (Currently Amended) The integrated circuit as recited in claim 1 wherein the  
integrated circuit deasserts the first temperature control signal, which is supplied on the first  
output terminal of the integrated circuit, according to a programmable mode of operation that  
includes at least one of deasserting when the temperature measurement falls below a

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programmable second temperature limit value and deasserting when a control location in the integrated circuit is accessed.

6. (Previously Presented) The integrated circuit as recited in claim 1 wherein the first temperature limit value is a panic value indicating a temperature limit for safe integrated circuit operation.

7. (Previously Presented) The integrated circuit as recited in claim 1 further comprising an addressable storage location coupled to the temperature sensor, the addressable storage location accessible by an instruction executed by the integrated circuit and supplying an indication of the temperature measurement on the integrated circuit.

8. (Previously Presented) The integrated circuit as recited in claim 1 further comprising: a second output terminal coupled to provide external to the integrated circuit an asserted signal when the temperature measurement indicated by the temperature sensor is above a second temperature limit value.

9. (Original) The integrated circuit as recited in claim 8 further comprising: a second storage location supplying the second temperature limit value; and second compare logic coupled to the second storage location and coupled to receive the temperature measurement of the integrated circuit, and wherein the second compare logic generates a second indication of when the temperature measurement of the integrated circuit is above the second temperature limit value.

10. (Original) The integrated circuit as recited in claim 9 further comprising: a third storage location supplying a third temperature limit value; third compare logic coupled to the third storage location and coupled to receive the temperature measurement, and wherein the compare logic generates a third indication that the temperature measurement of the integrated circuit is below the third temperature limit value.

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11. (Previously Presented) The integrated circuit as recited in claim 10 wherein the integrated circuit asserts a first temperature control signal which is supplied on a first output terminal of the integrated circuit when the temperature measurement indicated by the temperature sensor is below the third temperature limit value.

12. (Original) The integrated circuit as recited in claim 1 wherein the integrated circuit is a microprocessor.

13. (Currently Amended) A method comprising:  
measuring a temperature of an integrated circuit with a temperature sensor, the  
temperature sensor being a circuit within the integrated circuit;  
comparing the measured temperature to a first limit value stored in the integrated circuit;  
and  
generating a signal on a first output terminal of the integrated circuit according to the  
comparison to control the temperature of the integrated circuit,  
wherein the signal is asserted when the measured temperature is greater than the first  
limit value, and  
wherein the signal on the first output terminal is deasserted according to a programmable  
mode of operation that includes deasserting in response to at least one of either a  
control location on the integrated circuit being accessed and or the measured  
temperature falling below a lower limit value, according to a programmable mode  
of operation.

14. (Cancelled)

15. (Previously Presented) The method as recited in claim 13 wherein the asserted signal is used to inhibit a cooling device to control the temperature of the integrated circuit.

16 – 17. (Cancelled)

18. (Previously Presented) The method as recited in claim 13 wherein the signal is utilized to directly control a cooling device.

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19. (Cancelled)

20. (Previously Presented) A method comprising:  
measuring a temperature of an integrated circuit with a temperature sensor, the  
temperature sensor being a circuit within the integrated circuit;  
comparing the measured temperature to a first limit value stored in the integrated circuit;  
generating a signal on a first output terminal of the integrated circuit according to the  
comparison to control the temperature of the integrated circuit; and  
accessing a control location in the integrated circuit to cause the signal to be deasserted.

21. (Previously Presented) The method as recited in claim 13 wherein the asserted signal causes assertion of an interrupt and wherein a sequence of instructions, responsive to the asserted interrupt, activates a cooling device.

22. (Original) The method as recited in claim 21 wherein an instruction sequence causes the signal to be deasserted.

23. (Currently Amended) A method comprising:  
measuring a temperature of an integrated circuit with a temperature sensor, the  
temperature sensor being a circuit within the integrated circuit;  
comparing the measured temperature to a first limit value stored in the integrated circuit;  
and  
generating a signal on a first output terminal of the integrated circuit according to the  
comparison to control the temperature of the integrated circuit;  
comparing the measured temperature to a second limit value stored in the integrated  
circuit; and  
asserting a second signal on a second output terminal of the integrated circuit when the  
measured temperature is above the second limit value, thereby indicating that the  
temperature has exceeded a safe limit; and  
deasserting the second signal by accessing a control location in the integrated circuit.

24 – 25. (Cancelled)

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26. (Currently Amended) The apparatus as recited in claim ~~38~~ 25 wherein the apparatus is a computer system and further comprises at least one cooling device, which activates in response to an asserted signal on at least one of the two output terminals.

27. (Original) A microprocessor comprising:  
a temperature sensor providing a temperature measurement of the integrated circuit;  
at least a first and second temperature limit value stored in programmable storage locations in the microprocessor, the storage locations being accessible via software executed by the microprocessor;  
compare logic coupled to the temperature sensor and to the programmable storage locations storing the first and second temperature limit values, to provide respectively a first and second signal indicative of a comparison between the temperature measurement and the first and second temperature limit values; and  
first and second output terminals coupled to provide respectively, the first and second signals.

28. (Original) The microprocessor as recited in claim 27 wherein the microprocessor deasserts the first signal, which is supplied on the first output terminal of processor, when the temperature measurement falls below a programmable third temperature limit value, thereby providing a thermostat mode of operation for the first signal.

29. (Original) The integrated circuit as recited in claim 27 wherein the microprocessor includes a software accessible control register controlling operation of the compare logic and the first and second output terminals.

30 - 33. (Cancelled)

34. (Currently Amended) The ~~integrated circuit~~ microprocessor as recited in claim ~~27~~ 33 wherein the first ~~temperature control~~ signal is asserted in response to an ~~indication that the~~ measured temperature ~~exceeding~~s the first temperature limit, and wherein the first temperature

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~~control~~ signal is deasserted in response to ~~the second indication that the measured temperature~~  
~~does not exceeding~~ the second temperature limit.

35. (Cancelled)

36. (Currently Amended) The ~~integrated circuit~~ microprocessor as recited in claim ~~27~~  
~~33~~ further comprising ~~a third storage location to hold a control value stored in the programmable~~  
~~storage locations~~, and wherein a state of the first ~~temperature control~~ signal is controlled, at least  
in part by the control value.

37. (Currently Amended) The ~~integrated circuit~~ microprocessor as recited in claim ~~36~~  
~~33~~, wherein the first ~~temperature control~~ signal is asserted in response to ~~an indication that the~~  
measured temperature ~~exceedings~~ the first temperature limit, and wherein the first ~~temperature~~  
~~control~~ signal is deasserted in response to the control value.

38. (New) An apparatus comprising:

a processor that includes

control registers operable to host temperature limit values,

means for comparing a measured temperature to at least a first and second of the  
limit values,

means for providing a control signal on a first output terminal of the processor  
according to the comparison of the measured temperature to the first limit  
value, the control signal to control the temperature of the integrated  
circuit,

means for providing an indicator signal on a second output terminal of the  
integrated circuit when the measured temperature is above the second limit  
value, thereby indicating that the measured temperature has exceeded a  
safe limit; and

means for making the control registers accessible to software that monitors temperatures  
and sets a thermal management mode for the apparatus.

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39. (New) The apparatus of claim 38 further comprising means for mapping the control registers to an input/output space.

40. (New) The integrated circuit of claim 1, wherein a BIOS includes the instruction.

41. (New) The integrated circuit of claim 39 further comprising the BIOS executable to set addresses for the compare logic and to map the programmable storage location to an input/output space.

42. (New) The integrated circuit of claim 1, wherein the instruction is assigned a privilege level sufficient to access the programmable storage location.